

Semiconductor devices – Mechanical and climatic test methods —

Part 30: Preconditioning of non-hermetic surface mount devices prior to reliability testing

ICS 31.080.01

National foreword

This British Standard is the UK implementation of EN 60749-30:2005+A1:2011. It is identical to IEC 60749-30:2005, incorporating amendment 1:2011. It supersedes BS EN 60749-30:2005 which is withdrawn.

The start and finish of text introduced or altered by amendment is indicated in the text by tags. Tags indicating changes to IEC text carry the number of the IEC amendment. For example, text altered by IEC amendment 1 is indicated by **A1** *A1*.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments/corrigenda issued since publication

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**Semiconductor devices -
Mechanical and climatic test methods
Part 30: Preconditioning of non-hermetic surface mount devices
prior to reliability testing
(IEC 60749-30:2005)**

Dispositifs à semiconducteurs -
Méthodes d'essais mécaniques
et climatiques
Partie 30: Préconditionnement
des composants pour montage
en surface non hermétiques
avant les essais de fiabilité
(CEI 60749-30:2005)

Halbleiterbauelemente -
Mechanische und klimatische
Prüfverfahren
Teil 30: Behandlung nicht hermetisch
verkappter oberflächenmontierbarer
Bauelemente vor
Zuverlässigkeitsprüfungen
(IEC 60749-30:2005)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 47/1790/FDIS, future edition 1 of IEC 60749-30, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-30 on 2005-02-01.

The following dates were fixed:

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Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60749-30:2005 was approved by CENELEC as a European Standard without any modification.

Foreword to amendment A1

The text of document 47/2019/CDV, future amendment 1 to IEC 60749-30:2005, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as amendment A1 to EN 60749-30:2005 on 2011-06-29.

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Endorsement notice

The text of amendment 1:2011 to the International Standard IEC 60749-30:2005 was approved by CENELEC as an amendment to the European Standard without any modification.

CONTENTS

1	Scope	4
2	Normative references	4
3	General description	5
4	Test apparatus and materials.....	5
4.1	Moisture chamber.....	5
4.2	Solder equipment	5
4.3	Optical microscope	5
4.4	Electrical test equipment.....	5
4.5	Drying (bake) oven	6
4.6	Temperature cycle chamber (optional)	6
5	Procedure	6
5.1	General.....	6
5.2	Initial measurements.....	6
5.3	Temperature cycling (optional).....	6
5.4	Drying (bake out).....	6
5.5	Soak conditions for dry-packed SMDs	7
5.6	Soak conditions for non-dry-packed SMDs in accordance with IEC 60749-20:2008	7
5.7	Solder reflow	7
5.8	Flux application simulation (optional)	8
5.9	Final measurements	8
5.10	Applicable reliability tests	8
6	Summary.....	8
Table 1 – Preconditioning sequence flow – Method A (condition A2) in accordance with IEC 60749 20:2008 (dry-packed devices)		9
Table 2 – Preconditioning sequence flow – Method B (conditions B2 –B6) in accordance with IEC 60749-20:2008 (dry-packed devices)		10
Table 3 – Preconditioning sequence flow – Conditions A1 and B1 in accordance with IEC 60749-20:2008 (non dry-packed devices)		11
Annex ZA (normative) Normative references to international publications with their corresponding European publications		12